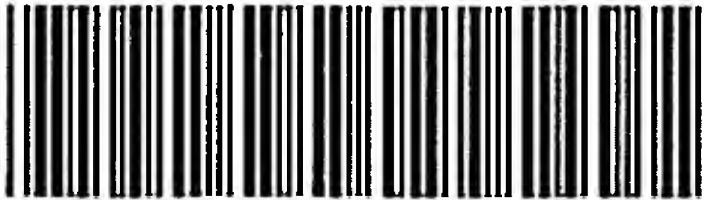


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/004,805	SHIMIZU ET AL.	
	Examiner	Art Unit	
	A. Sefer	2826	

SEARCHED			
Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
349	155-158	6/2/2006	AS
	162	6/2/2006	AS

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST (USPAT, US-PG-Pub, Derwent, EPO & JPO)	6/2/2006	AS
349/155-158,162 (text search)	6/2/2006	AS